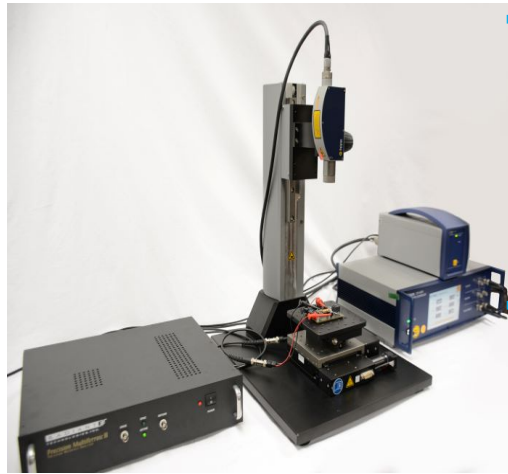


Thin Film Piezoelectric Test Bundle - NLV

Polytec Laser Vibrometers attached to a Radiant Test System accurately measure the piezoelectric coefficient (d33) of thin piezoelectric films deposited on cantilevers and membranes or clamped to a substrate.

- ✓ **Accurate**
- ✓ **Reproducible**
- ✓ **Simple to Operate**
- ✓ **Versatile**
- ✓ **Flexible**

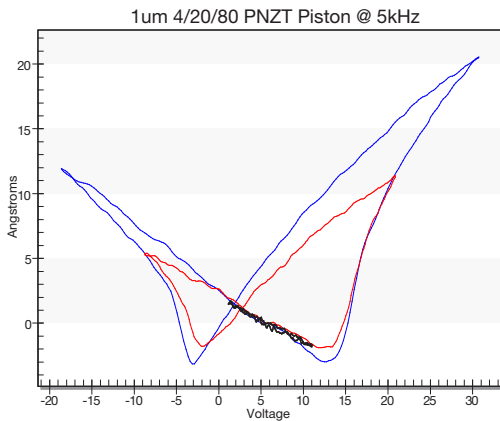


Radiant's PiezoMEMS Analyzer, Multiferroic II and Precision LCII Testers use 18-bit ADC's, have 76 microvolt per bit resolution, and exhibit a noise floor of ~300µV for a single pass

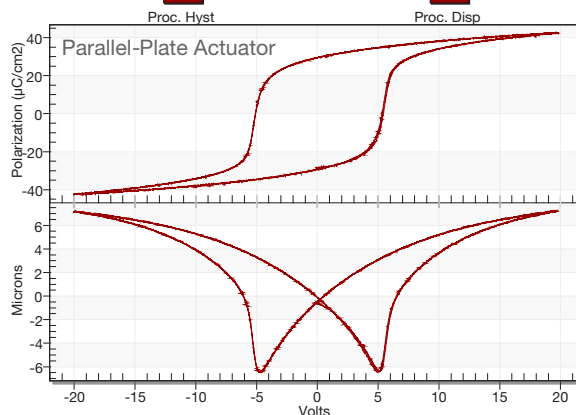
The Thin Film Piezo Test Bundle can reach 0.2 Angstrom (0.02nm) resolution in d33 piston motion with the Polytec NLV

- The 2µm spot size is perfectly suited for measuring production pMEMS devices in situ.

Butterfly Motion



d33 with NLV



Angstrom-level clamped thin piezoelectric film measurement

For More Information on the Thin Film Piezoelectric Test Bundle contact Radiant Technologies, Inc at

505.842.8007